



PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Jeffrey T. Fanton et al.

Application No.: 10/053,373

Filed: October 24, 2001

For: X-RAY REFLECTANCE  
MEASUREMENT SYSTEM WITH  
ADJUSTABLE RESOLUTION

Group No.: 2882

Examiner: I. Kiknadze

**ASSOCIATE POWER OF ATTORNEY**

121 Spear Street, Suite 290  
San Francisco, CA 94105  
Telephone: 415-512-1312  
Facsimile: 415-512-1362

M/S NON-FEE AMENDMENT  
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P.O. Box 1450  
Alexandria, VA 22313-1450

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STALLMAN & POLLOCK LLP

Dated: 10/2/2003

By:

*Georgia K. Stith*  
Georgia K. Stith

Sir:

Please recognize as Associate Patent Attorney in this case:

Name of Attorney: Jason D. Lohr

Address: 121 Spear Street, Suite 290  
San Francisco, CA 94111

Reg. No.: 48,163

Telephone: (415) 512-1312

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Signature of Principal Attorney of Record

Date: October 1, 2003

By:

*Michael A. Stallman*

Michael A. Stallman (Reg. No. 29,444)

Attorneys for Applicant(s)